SCAS514C - JUNE 1995 - REVISED SEPTEMBER 1996

- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Flat (W), and DIP (J, N) Packages

#### description

These octal buffers and line drivers are designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

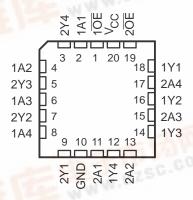
The 'AC244 are organized as two 4-bit buffers/drivers with separate output-enable ( $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes noninverted data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

The SN54AC244 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74AC244 is characterized for operation from -40°C to 85°C.

SN54AC244 . . . J OR W PACKAGE SN74AC244 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



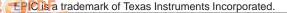
## SN54AC244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer)

(000111001101)									
INP	JTS	OUTPUT							
OE	Α	Y							
L	Н	Н							
L	L	L							
Н	Χ	Z							

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

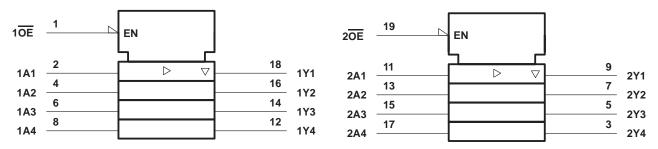




### SN54AC244, SN74AC244 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

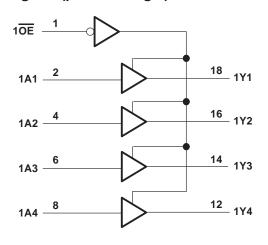
SCAS514C – JUNE 1995 – REVISED SEPTEMBER 1996

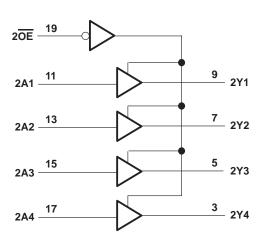
#### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive Logic)





## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Output voltage range, VO (see Note 1)	0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ )	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2):	DB package 0.6 W
	DW package 1.6 W
	N package 1.3 W
	PW package 0.7 W
Storage temperature range, T <sub>stq</sub>	

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>2.</sup> The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

### recommended operating conditions (see Note 3)

			SN54A	N54AC244 SN74AC244		UNIT	
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		2	6	2	6	V
		V <sub>CC</sub> = 3 V	2.1		2.1		
VIH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15		3.15		V
		V <sub>CC</sub> = 5.5 V	3.85		3.85		
		V <sub>CC</sub> = 3 V		0.9		0.9	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V		1.35		1.35	V
		V <sub>CC</sub> = 5.5 V		1.65		1.65	
٧ <sub>I</sub>	Input voltage		0	VCC	0	VCC	V
٧o	Output voltage		0	VCC	0	VCC	V
		V <sub>CC</sub> = 3 V		-12		-12	
ІОН	High-level output current	V <sub>CC</sub> = 4.5 V		-24		-24	mA
		V <sub>CC</sub> = 5.5 V		-24		-24	
		V <sub>CC</sub> = 3 V		12		12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V		24		24	mA
	V <sub>CC</sub> = 5.5 V			24		24	
Δt/Δν	Input transition rise or fall rate		0	8	0	8	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

## SN54AC244, SN74AC244 OCTAL BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCAS514C – JUNE 1995 – REVISED SEPTEMBER 1996

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DAMETED	TEST CONDITIONS	V	T	_ = 25°C		SN54A	C244	SN74AC244		UNIT	
PARAMETER		TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
			3 V	2.9			2.9		2.9			
$I_{OH} = -50 \mu\text{A}$ 4.5 V 4.4 4.4 5.5 V 5.4 5.4 VOH		I <sub>OH</sub> = -50 μA	4.5 V	4.4			4.4		4.4			
		5.5 V	5.4			5.4		5.4				
		2.46		V								
VOH		24 4	4.5 V	3.86			3.7		3.76		V	
		I <sub>OL</sub> = -24 mA	5.5 V	4.86			4.7		4.76			
		$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85					
	$I_{OH} = -75 \text{ mA}^{\dagger}$ $3 \text{ V}$				3.85							
			3 V			0.1		0.1		0.1		
	$I_{OL} = 50 \mu A$	4.5 V			0.1		0.1		0.1			
		5.5 V			0.1		0.1		0.1			
VOL	Va	I <sub>OL</sub> = 12 mA	3 V			0.36		0.5		0.44	V	
VOL		I <sub>OL</sub> = 24 mA	4.5 V			0.36		0.5		0.44	·	
		10[ - 24 11]	5.5 V			0.36		0.5		0.44		
		$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65				
		$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65		
ł <sub>I</sub>	Data inputs	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V			±0.1		±1		±1	μА	
''	Control inputs	V <sub>I</sub> = V <sub>CC</sub> or GND	3.5 V			±0.1		±1		±1	μΛ	
loz		$V_O = V_{CC}$ or GND, $V_{I(OE)} = V_{IL}$ or $V_{IH}$	5.5 V			±0.25		±5		±2.5	μА	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ	
Ci		$V_I = V_{CC}$ or GND	5 V		2.5						pF	

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T <sub>A</sub> = 25°C			SN54AC244		SN74AC244		UNIT	
	(INPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
<sup>t</sup> PLH	А	V	2	6.5	9	1	12.5	1.5	10	ns	
<sup>t</sup> PHL		T	2	6.5	9	1	12	2	10	115	
<sup>t</sup> PZH	<del></del>			2	6	10.5	1	11.5	1.5	11	no
<sup>t</sup> PZL	ŌĒ	ī	2.5	7.5	10	1	13	2	11	ns	
t <sub>PHZ</sub>	ŌĒ	tPHZ OF	V	3	7	10	1	12.5	1.5	10.5	20
t <sub>PLZ</sub>	OE	Ĭ	2.5	7.5	10.5	1	13	2.5	11.5	ns	



SCAS514C - JUNE 1995 - REVISED SEPTEMBER 1996

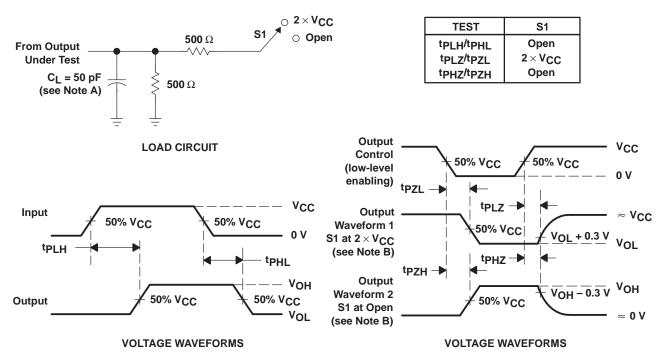
## switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T <sub>A</sub> = 25°C			SN54AC244		SN74AC244		UNIT	
	(INPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
<sup>t</sup> PLH	A		1.5	5	7	1	9.5	1	7.5	ns	
<sup>t</sup> PHL		ī	1.5	5	7	1	9	1	7.5	115	
<sup>t</sup> PZH	ŌĒ	V	1.5	5	7	1	9	1.5	8	ns	
t <sub>PZL</sub>		Ĭ	1.5	5.5	8	1	10.5	1.5	8.5	115	
<sup>t</sup> PHZ	ŌĒ	<u></u>	<b>&gt;</b>	2.5	6.5	9	1	10.5	1	9.5	ne
t <sub>PLZ</sub>	J OE	·	2	6.5	9	1	11	2	9.5	ns	

#### operating characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

PARAMETER		TEST CON	TYP	UNIT	
C <sub>pd</sub>	Power dissipation capacitance per buffer/driver	$C_L = 50 \text{ pF},$	f = 1 MHz	45	pF

### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics:  $PRR \le 1 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_f \le 2.5 \text{ ns}$ ,  $t_f \le 2.5 \text{ ns}$ .
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



#### **IMPORTANT NOTICE**

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated